


<b>Search Notes</b>  	<b>Application/Control No.</b>  10540311	<b>Applicant(s)/Patent Under Reexamination</b>  AUGUSTUS ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
re-reviewed the STIC-assisted search of SEQ ID Numbers 1 and 7	5/29/2009	/YJK/
STIC- search reviewed	1/8/2010	/YJK/
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text-search strategy	1/8/2010	/YJK/
updated	8/2/2010	/YJK/
updated patent database search (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text-search strategy	11/22/2010	/YJK/
updated	2/15/2011	/YJK/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference search history - see enclosed	1/8/2010	/YJK/
	updated interference search - see enclosed for strategy	11/22/2010	/YJK/

	/Young J Kim/ Primary Examiner.Art Unit 1637
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